

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination SAINT ETIENNE ET AL.	
		Examiner Feben M. Haile	Art Unit 2616	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0152077	08-2003	Saint Etienne et al.	370/389
*	B	US-6,188,689	02-2001	Katsube et al.	370/389
*	C	US-6,282,669	08-2001	Imanaka et al.	714/4
*	D	US-6,799,037	09-2004	Mielke et al.	455/435.1
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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